

Application No.: 10/538,522
Amendment dated: July 24, 2006
Reply to Office Action of February 22, 2006
Attorney Docket No.: 21295.0106US1 (E0664US)

Aeg 4/3/08

a.) Amendments to Specification

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Replace the paragraph beginning at page 1, paragraph [010], in the specification as originally filed, with the following rewritten paragraph:

-- This task is solved by the reflected-light microscope, which comprises a light source to generate an illumination light beam that can be directed through a lens that exhibits with a pupil lens on a pupil plane; along an illumination beam path and onto a sample; an An imaging optics that generates an optically corresponding plane to the pupil plane, in which case at least one attenuation element that acts in an essentially uniform manner over the entire cross-section of the illumination light beam can be introduced into the illumination beam path on the optically corresponding plane.--

Replace the paragraph beginning at page 1, paragraph [012], in the specification as originally filed, with the following rewritten paragraph:

--Because the attenuating element according to the invention is arranged in the illumination light beam on a plane that corresponds optically to the pupil plane of the lens--that is, on a Fourier plane of the pupil plane of the lens, which Fourier plane is to the focal plane of the imaging optics, lens--the structure of the attenuation element, which can, for example, have a grate or sieve structure, is not visible in the sample plane being observed. The sample is consequently not illuminated with a sieve pattern or a pinhole pattern; rather, illumination is reduced over the entire image field. At the same time, undesired changes in light power are avoided because the attenuation element acts over the entire cross-section of the illumination light beam and not just over marginal areas.--

Replace the paragraph beginning at page 1, paragraph [023], in the specification as originally filed, with the following rewritten paragraph:

-- FIG. 1 shows a reflected-light microscope according to the invention with a light source 1 for generating an illumination light beam 3. The illumination light beam 3 is